# HM62W16255HCI Series

Wide Temperature Range Version
4M High Speed SRAM (256-kword × 16-bit)

HITACHI

ADE-203-1263A (Z)

Rev. 1.0
Nov. 1, 2001

## Description

The HM62W16255HCI is a 4-Mbit high speed static RAM organized 256-kword × 16-bit. It has realized high speed access time by employing CMOS process (6-transistor memory cell) and high speed circuit designing technology. It is most appropriate for the application which requires high speed, high density memory and wide bit width configuration, such as cache and buffer memory in system. The HM62W16255HCI is packaged in 400-mil 44-pin SOJ and 400-mil 44-pin plastic TSOPII for high density surface mounting.

## Features

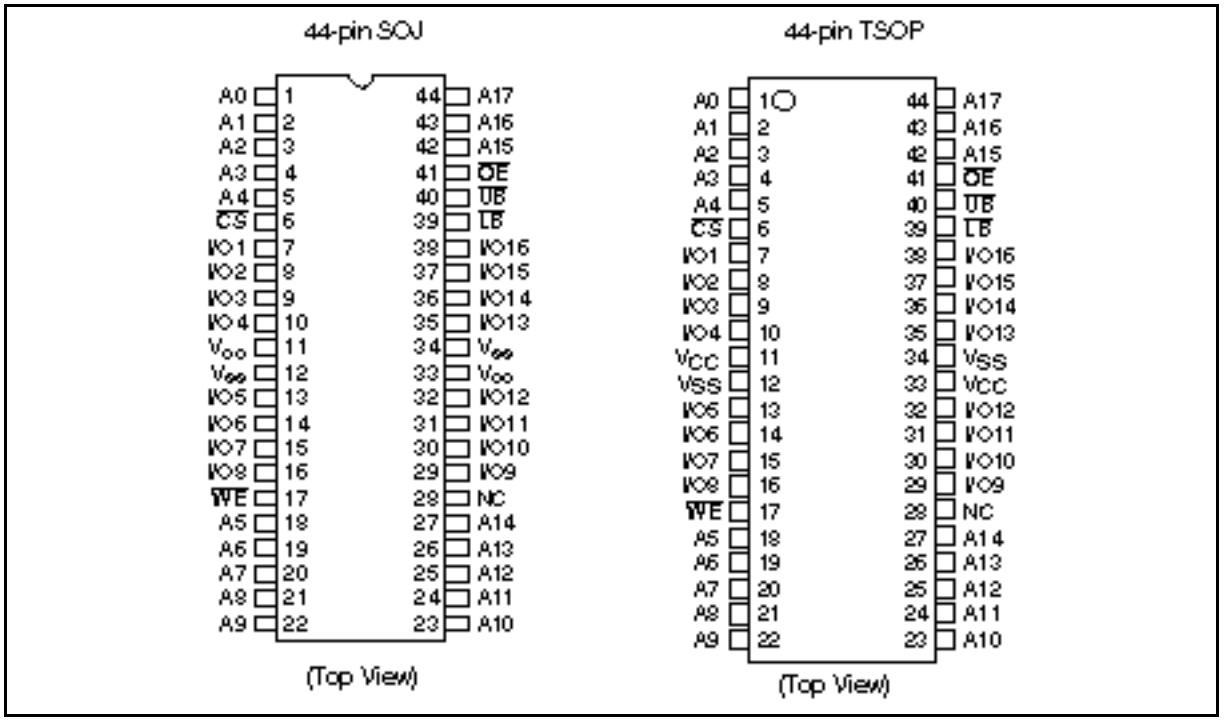
- Single 3.3 V supply: 3.3 V ± 0.3 V
- Access time: 12 ns (max)
- Completely static memory
  - — No clock or timing strobe required
- Equal access and cycle times
- Directly TTL compatible
  - — All inputs and outputs
- Operating current: 130 mA (max)
- TTL standby current: 40 mA (max)
- CMOS standby current: 5 mA (max)
- Center $V_{CC}$ and $V_{SS}$ type pinout
- Temperature range: –40 to +85°C

Hitachi semiconductor

## Ordering Information

| Type No. | Access time | Device marking | Package |
|---|---|---|---|
| HM62W16255HCJPI-12 | 12 ns | HM62W16255CJPI12 | 400-mil 44-pin plastic SOJ (CP-44D) |
| HM62W16255HCTTI-12 | 12 ns | HM62W16255CTTI12 | 400-mil 44-pin plastic TSOPII (TTP-44DE) |

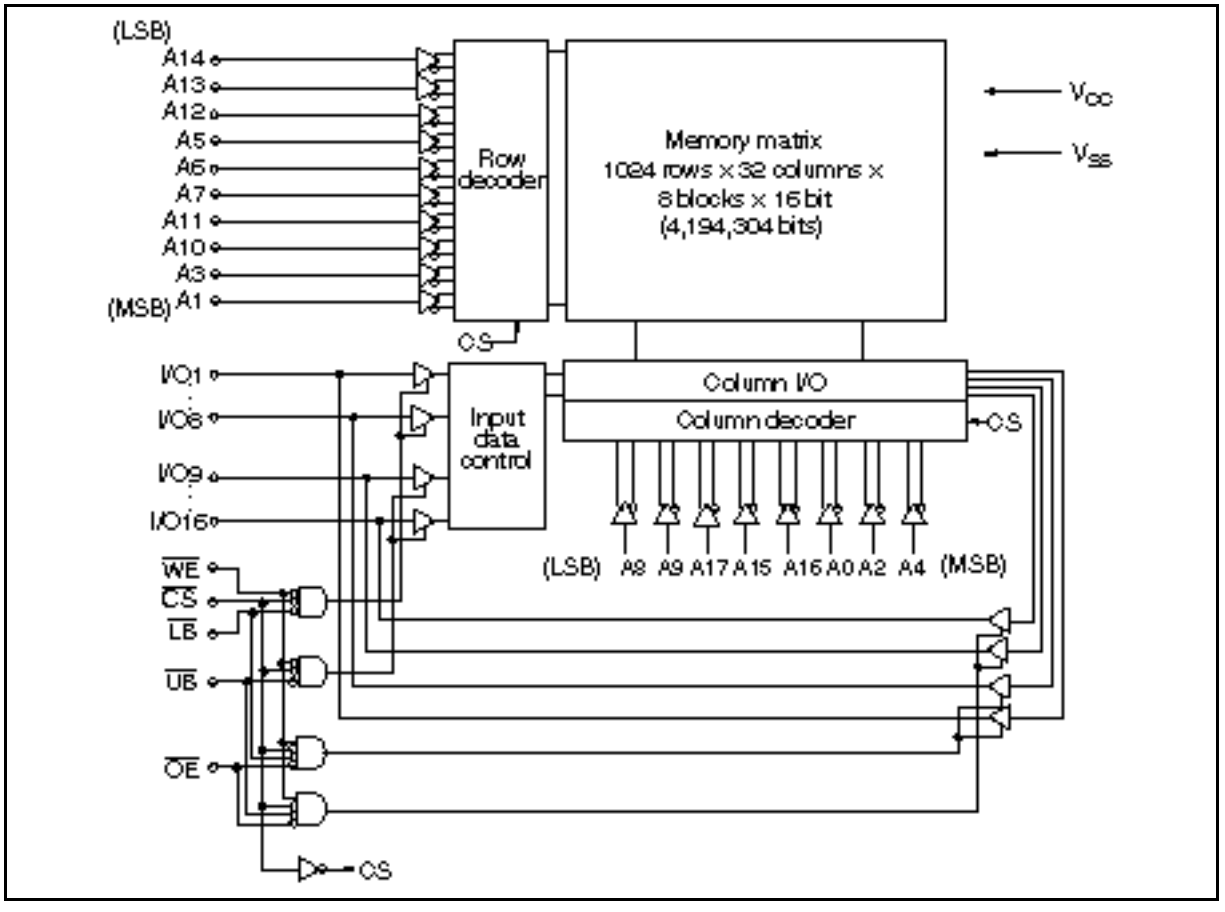
## Pin Arrangement




## Pin Description

| Pin name | Function |
|---|---|
| A0 to A17 | Address input |
| I/O1 to I/O16 | Data input/output |
| CS | Chip select |
| OE | Output enable |
| WE | Write enable |
| UB | Upper byte select |
| LB | Lower byte select |
| $V_{CC}$ | Power supply |
| $V_{SS}$ | Ground |
| NC | No connection |

## Block Diagram



## Operation Table

| CS | OE | WE | LB | UB | Mode | $V_{CC}$ current | I/O1–I/O8 | I/O9–I/O16 | Ref. cycle |
|---|---|---|---|---|---|---|---|---|---|
| H | × | × | × | × | Standby | $I_{SB}$, $I_{SB1}$ | High-Z | High-Z | — |
| L | H | H | × | × | Output disable | $I_{CC}$ | High-Z | High-Z | — |
| L | L | H | L | L | Read | $I_{CC}$ | Output | Output | Read cycle |
| L | L | H | L | H | Lower byte read | $I_{CC}$ | Output | High-Z | Read cycle |
| L | L | H | H | L | Upper byte read | $I_{CC}$ | High-Z | Output | Read cycle |
| L | L | H | H | H | — | $I_{CC}$ | High-Z | High-Z | — |
| L | × | L | L | L | Write | $I_{CC}$ | Input | Input | Write cycle |
| L | × | L | L | H | Lower byte write | $I_{CC}$ | Input | High-Z | Write cycle |
| L | × | L | H | L | Upper byte write | $I_{CC}$ | High-Z | Input | Write cycle |
| L | × | L | H | H | — | $I_{CC}$ | High-Z | High-Z | — |

Note: H: $V_{IH}$, L: $V_{IL}$, ×: $V_{IH}$ or $V_{IL}$

## Absolute Maximum Ratings

| Parameter | Symbol | Value | Unit |
|---|---|---|---|
| Supply voltage relative to $V_{SS}$ | $V_{CC}$ | –0.5 to +4.6 | V |
| Voltage on any pin relative to $V_{SS}$ | $V_T$ | –0.5*[1] to $V_{CC}$ + 0.5*[2] | V |
| Power dissipation | $P_T$ | 1.0 | W |
| Operating temperature | Topr | –40 to +85 | °C |
| Storage temperature | Tstg | –55 to +125 | °C |
| Storage temperature under bias | Tbias | –40 to +85 | °C |

Notes: 1. $V_T$ (min) = –2.0 V for pulse width (under shoot) ≤ 6 ns
2. $V_T$ (max) = $V_{CC}$ + 2.0 V for pulse width (over shoot) ≤ 6 ns

## Recommended DC Operating Conditions

(Ta = –40 to +85°C)

| Parameter | Symbol | Min | Typ | Max | Unit |
|---|---|---|---|---|---|
| Supply voltage | $V_{CC}$*3 | 3.0 | 3.3 | 3.6 | V |
| | $V_{SS}$*4 | 0 | 0 | 0 | V |
| Input voltage | $V_{IH}$ | 2.0 | — | $V_{CC}$ + 0.5*2 | V |
| | $V_{IL}$ | –0.5*1 | — | 0.8 | V |

Notes: 1. $V_{IL}$ (min) = –2.0 V for pulse width (under shoot) ≤ 6 ns
2. $V_{IH}$ (max) = $V_{CC}$ + 2.0 V for pulse width (over shoot) ≤ 6 ns
3. The supply voltage with all $V_{CC}$ pins must be on the same level.
4. The supply voltage with all $V_{SS}$ pins must be on the same level.

## DC Characteristics

(Ta = –40 to +85°C, $V_{CC}$ = 3.3 V ± 0.3 V, $V_{SS}$ = 0 V)

| Parameter | Symbol | Min | Typ*1 | Max | Unit | Test conditions |
|---|---|---|---|---|---|---|
| Input leakage current | $\|I_{LI}\|$ | — | — | 2 | µA | Vin = $V_{SS}$ to $V_{CC}$ |
| Output leakage current | $\|I_{LO}\|$ | — | — | 2 | µA | Vin = $V_{SS}$ to $V_{CC}$ |
| Operating power supply current | $I_{CC}$ | — | — | 130 | mA | Min cycle<br>CS = $V_{IL}$, Iout = 0 mA<br>Other inputs = $V_{IH}$/$V_{IL}$ |
| Standby power supply current | $I_{SB}$ | — | — | 40 | mA | Min cycle, CS = $V_{IH}$,<br>Other inputs = $V_{IH}$/$V_{IL}$ |
| | $I_{SB1}$ | — | 2.5 | 5 | mA | f = 0 MHz<br>$V_{CC}$ ≥ CS ≥ $V_{CC}$ – 0.2 V,<br>(1) 0 V ≤ Vin ≤ 0.2 V or<br>(2) $V_{CC}$ ≥ Vin ≥ $V_{CC}$ – 0.2 V |
| Output voltage | $V_{OL}$ | — | — | 0.4 | V | $I_{OL}$ = 8 mA |
| | $V_{OH}$ | 2.4 | — | — | V | $I_{OH}$ = –4 mA |

Notes: 1. Typical values are at $V_{CC}$ = 3.3 V, Ta = +25°C and not guaranteed.

## Capacitance

(Ta = +25°C, f = 1.0 MHz)

| Parameter | Symbol | Min | Typ | Max | Unit | Test conditions |
|---|---|---|---|---|---|---|
| Input capacitance*[1] | Cin | — | — | 6 | pF | Vin = 0 V |
| Input/output capacitance*[1] | $C_{I/O}$ | — | — | 8 | pF | $V_{I/O}$ = 0 V |

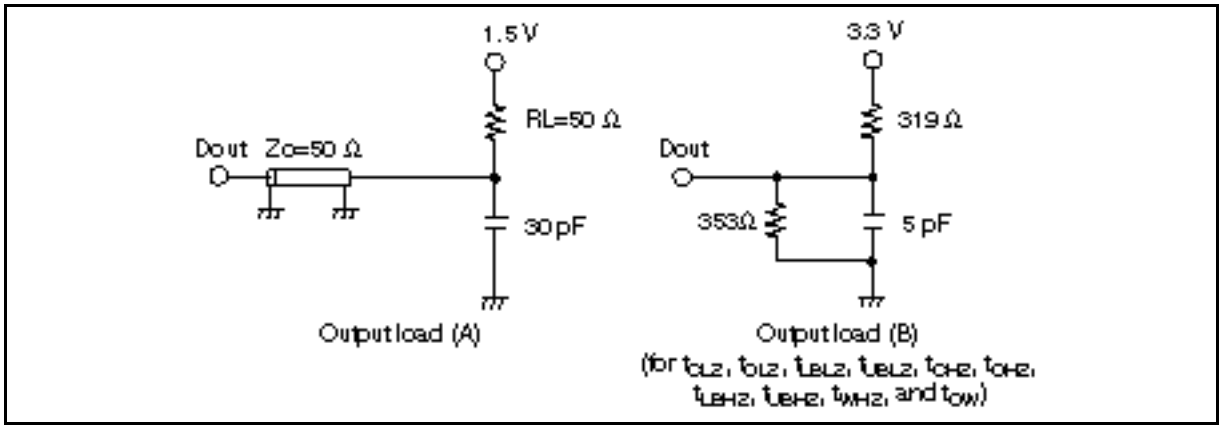
Note: 1. This parameter is sampled and not 100% tested.

## AC Characteristics

(Ta = –40 to +85°C, $V_{CC}$ = 3.3 V ± 0.3 V, unless otherwise noted.)

**Test Conditions**

- Input pulse levels: 3.0 V/0.0 V
- Input rise and fall time: 3 ns
- Input and output timing reference levels: 1.5 V
- Output load: See figures (Including scope and jig)




**Read Cycle**

| | | HM62W16255HCI | | | |
|---|---|---|---|---|---|
| | | -12 | | | |
| **Parameter** | **Symbol** | **Min** | **Max** | **Unit** | **Notes** |
| Read cycle time | $t_{RC}$ | 12 | — | ns | |
| Address access time | $t_{AA}$ | — | 12 | ns | |
| Chip select access time | $t_{ACS}$ | — | 12 | ns | |
| Output enable to output valid | $t_{OE}$ | — | 6 | ns | |
| Byte select to output valid | $t_{LB}$, $t_{UB}$ | — | 6 | ns | |
| Output hold from address change | $t_{OH}$ | 3 | — | ns | |
| Chip select to output in low-Z | $t_{CLZ}$ | 3 | — | ns | 1 |
| Output enable to output in low-Z | $t_{OLZ}$ | 0 | — | ns | 1 |
| Byte select to output in low-Z | $t_{LBLZ}$, $t_{UBLZ}$ | 0 | — | ns | 1 |
| Chip deselect to output in high-Z | $t_{CHZ}$ | — | 6 | ns | 1 |
| Output disable to output in high-Z | $t_{OHZ}$ | — | 6 | ns | 1 |
| Byte deselect to output in high-Z | $t_{LBHZ}$, $t_{UBHZ}$ | — | 6 | ns | 1 |

**Write Cycle**

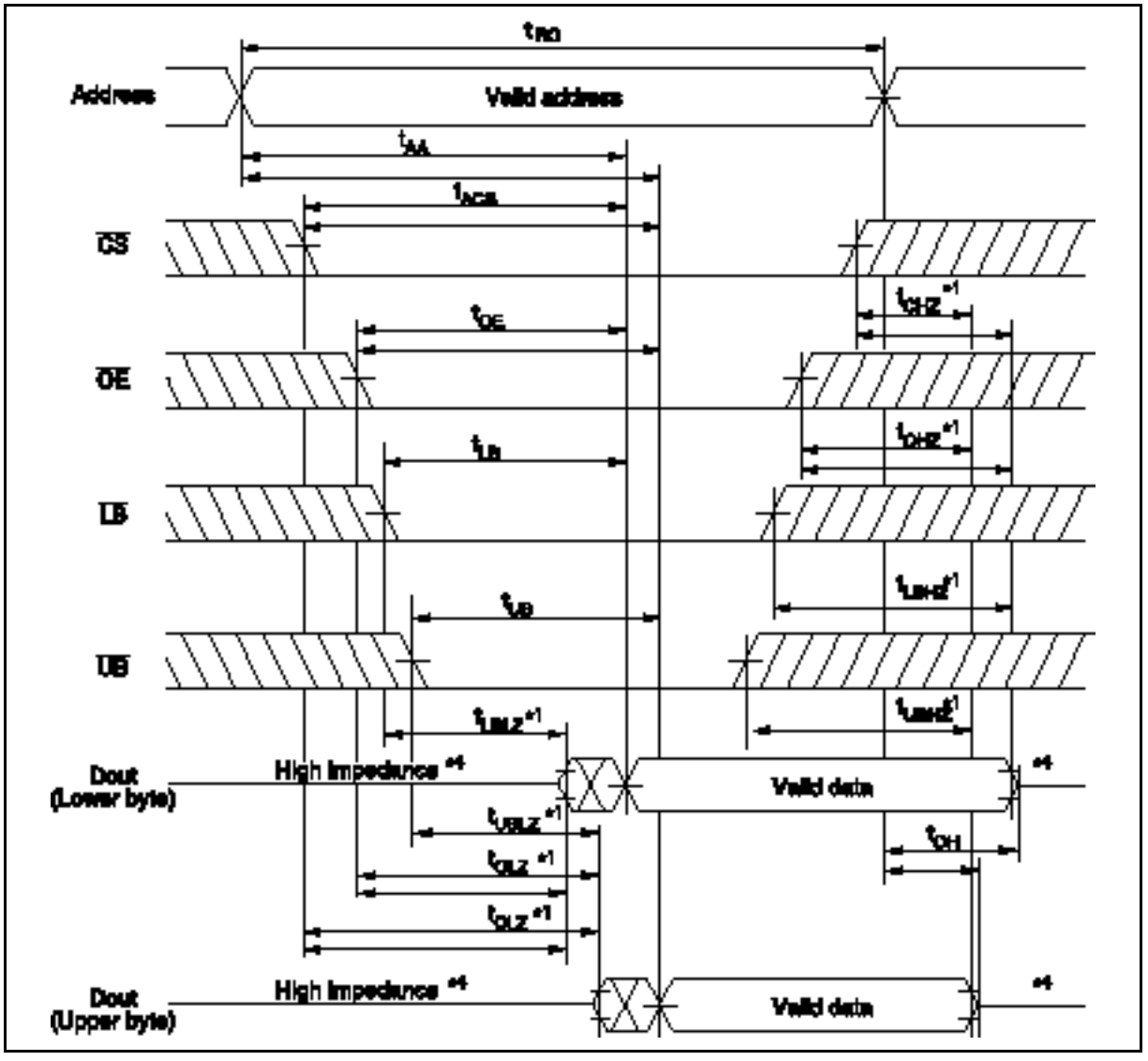
| | | HM62W16255HCI | | | |
|---|---|---|---|---|---|
| | | -12 | | | |
| **Parameter** | **Symbol** | **Min** | **Max** | **Unit** | **Notes** |
| Write cycle time | $t_{WC}$ | 12 | — | ns | |
| Address valid to end of write | $t_{AW}$ | 8 | — | ns | |
| Chip select to end of write | $t_{CW}$ | 8 | — | ns | 8 |
| Write pulse width | $t_{WP}$ | 8 | — | ns | 7 |
| Byte select to end of write | $t_{LBW}$, $t_{UBW}$ | 8 | — | ns | 9, 10 |
| Address setup time | $t_{AS}$ | 0 | — | ns | 5 |
| Write recovery time | $t_{WR}$ | 0 | — | ns | 6 |
| Data to write time overlap | $t_{DW}$ | 6 | — | ns | |
| Data hold from write time | $t_{DH}$ | 0 | — | ns | |
| Write disable to output in low-Z | $t_{OW}$ | 3 | — | ns | 1 |
| Output disable to output in high-Z | $t_{OHZ}$ | — | 6 | ns | 1 |
| Write enable to output in high-Z | $t_{WHZ}$ | — | 6 | ns | 1 |

Notes: 1. Transition is measured ±200 mV from steady voltage with output load (B). This parameter is sampled and not 100% tested.

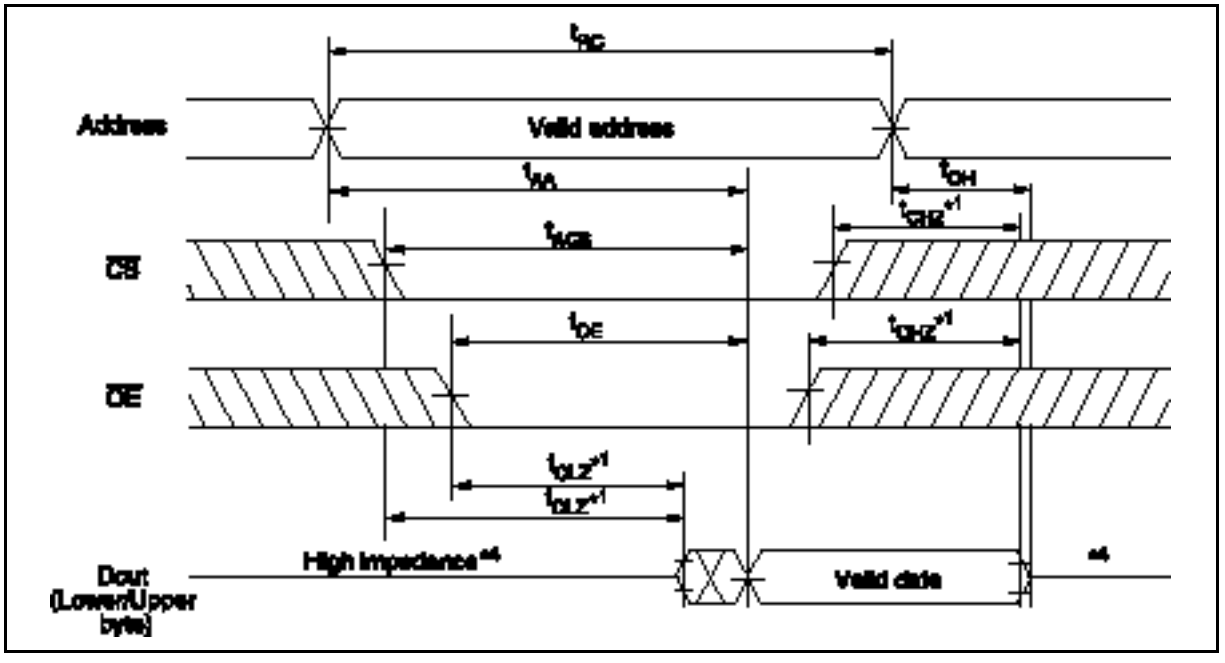
2. If the CS or LB or UB low transition occurs simultaneously with the WE low transition or after the WE transition, output remains a high impedance state.
3. WE and/or CS must be high during address transition time.
4. If CS, OE, LB and UB are low during this period, I/O pins are in the output state. Then the data input signals of opposite phase to the outputs must not be applied to them.
5. $t_{AS}$ is measured from the latest address transition to the latest of CS, WE, LB or UB going low.
6. $t_{WR}$ is measured from the earliest of CS, WE, LB or UB going high to the first address transition.
7. A write occurs during the overlap of low CS, low WE and low LB or low UB.
8. $t_{CW}$ is measured from the later of CS going low to the end of write.
9. $t_{LBW}$ is measured from the later of LB going low to the end of write.
10. $t_{UBW}$ is measured from the later of UB going low to the end of write.

## Timing Waveforms

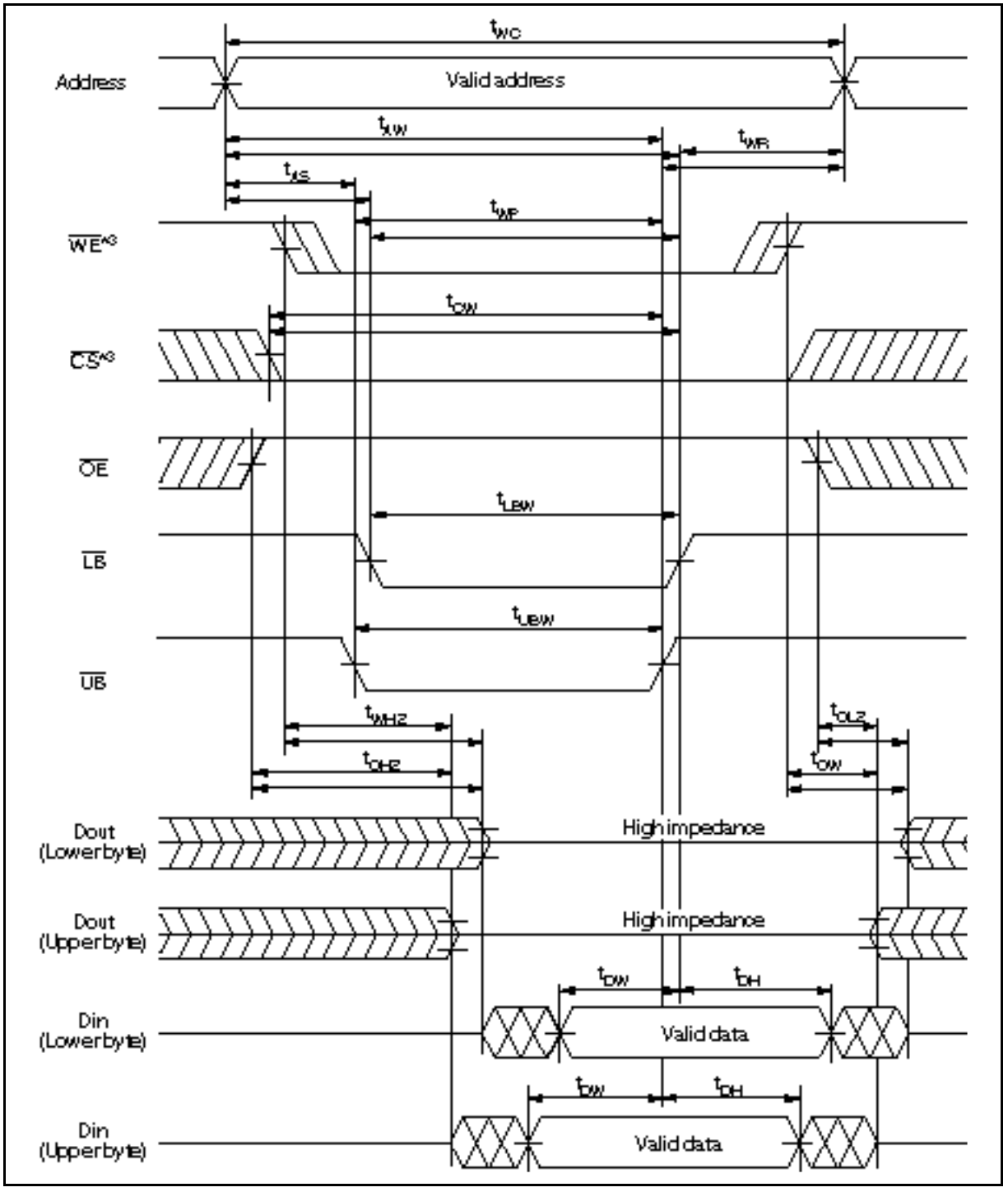
**Read Timing Waveform (1)** (WE = $V_{IH}$)



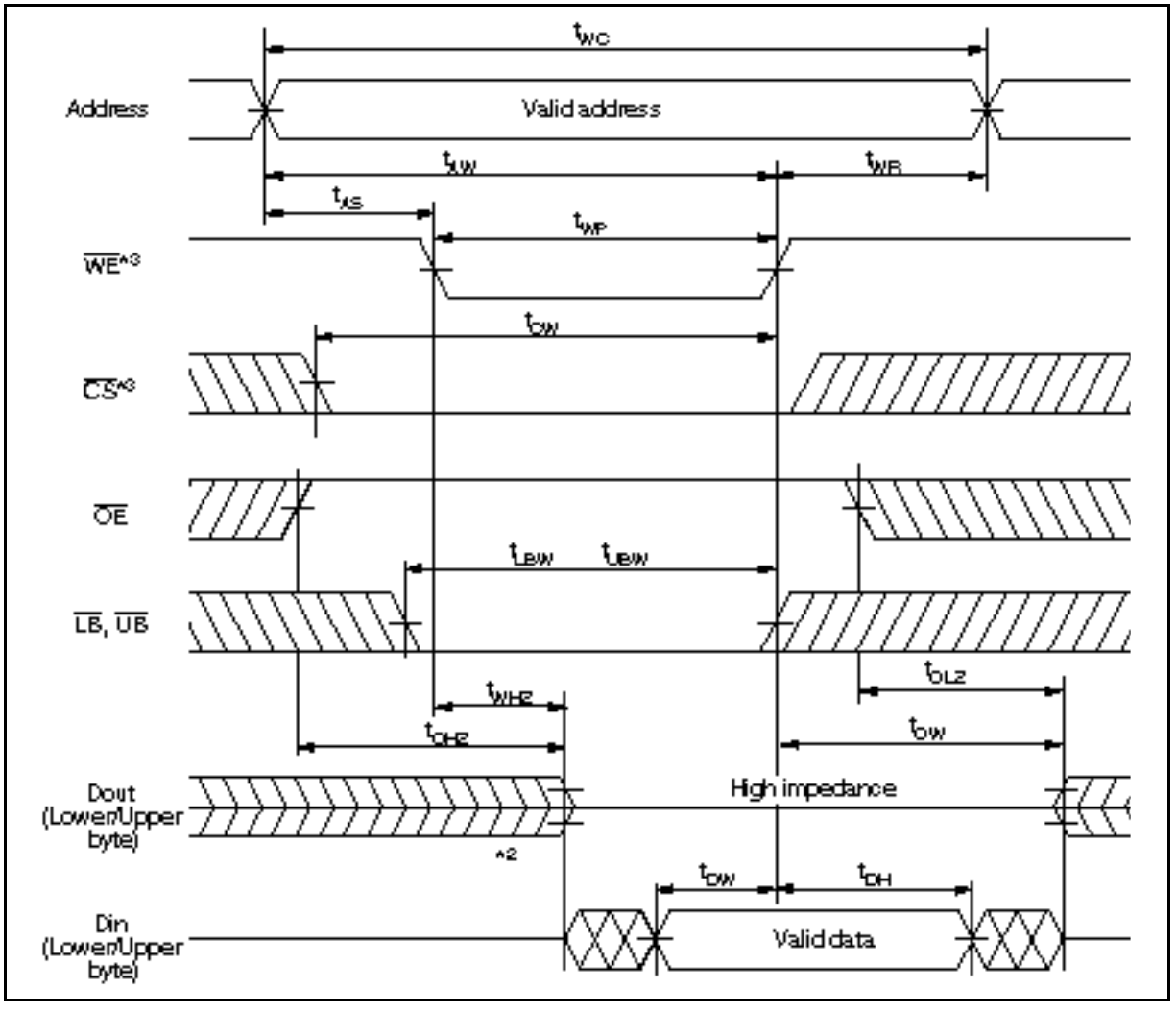
**Read Timing Waveform (2) ($\overline{WE}$ = $V_{IH}$, $\overline{LB}$ = $V_{IL}$, $\overline{UB}$, = $V_{IL}$)**



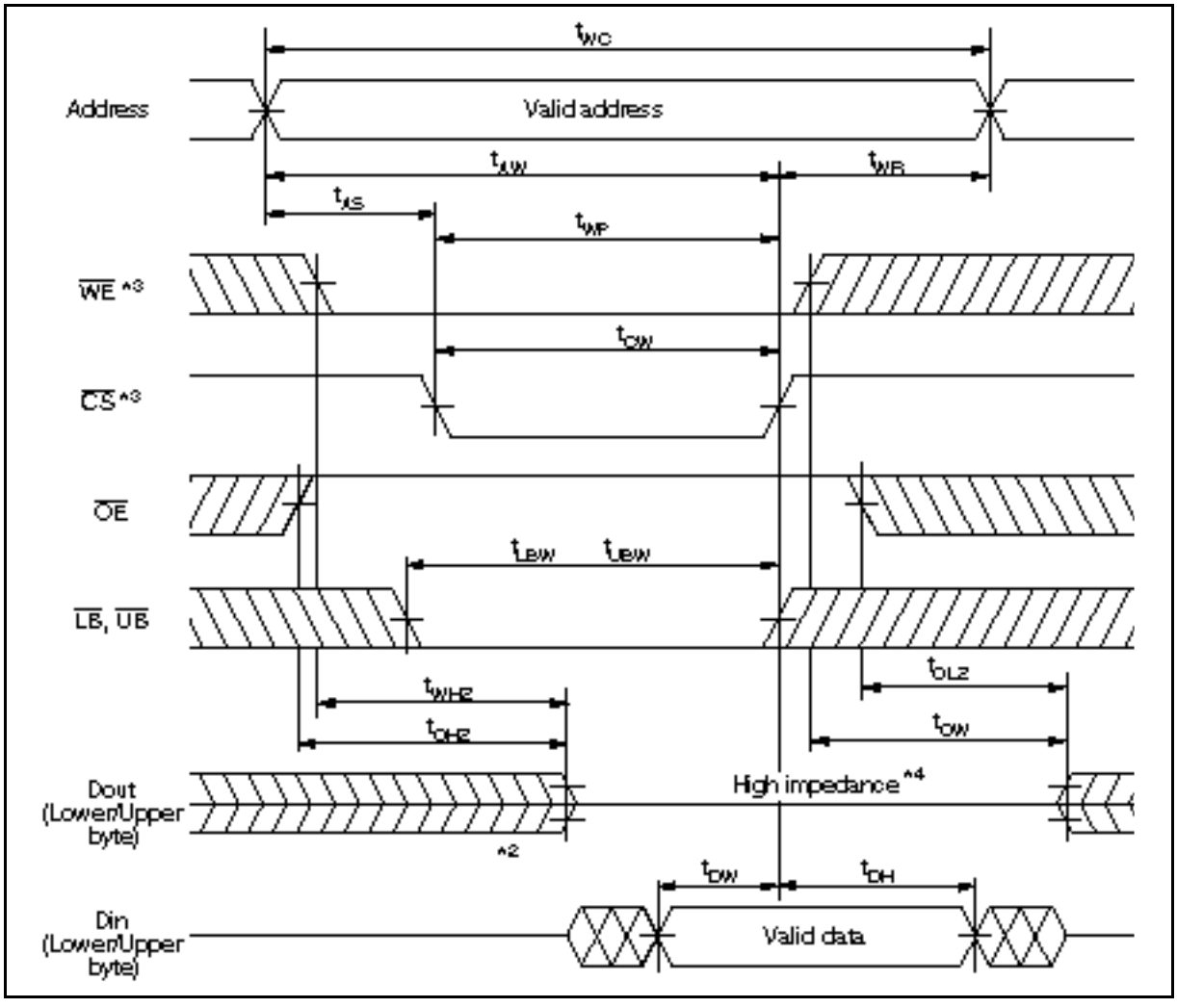
**Write Timing Waveform (1)** (LB, UB Controlled)



**Write Timing Waveform (2)** (WE Controlled)

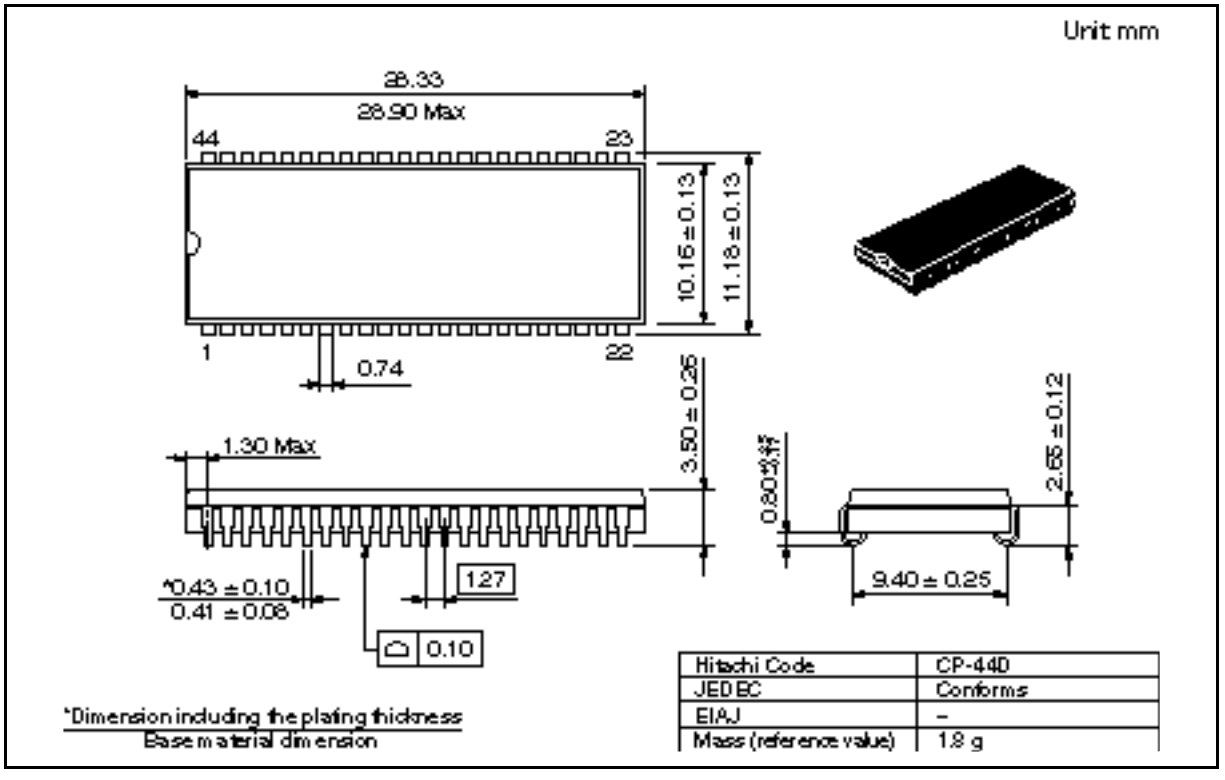


**Write Timing Waveform (3)** (CS Controlled)



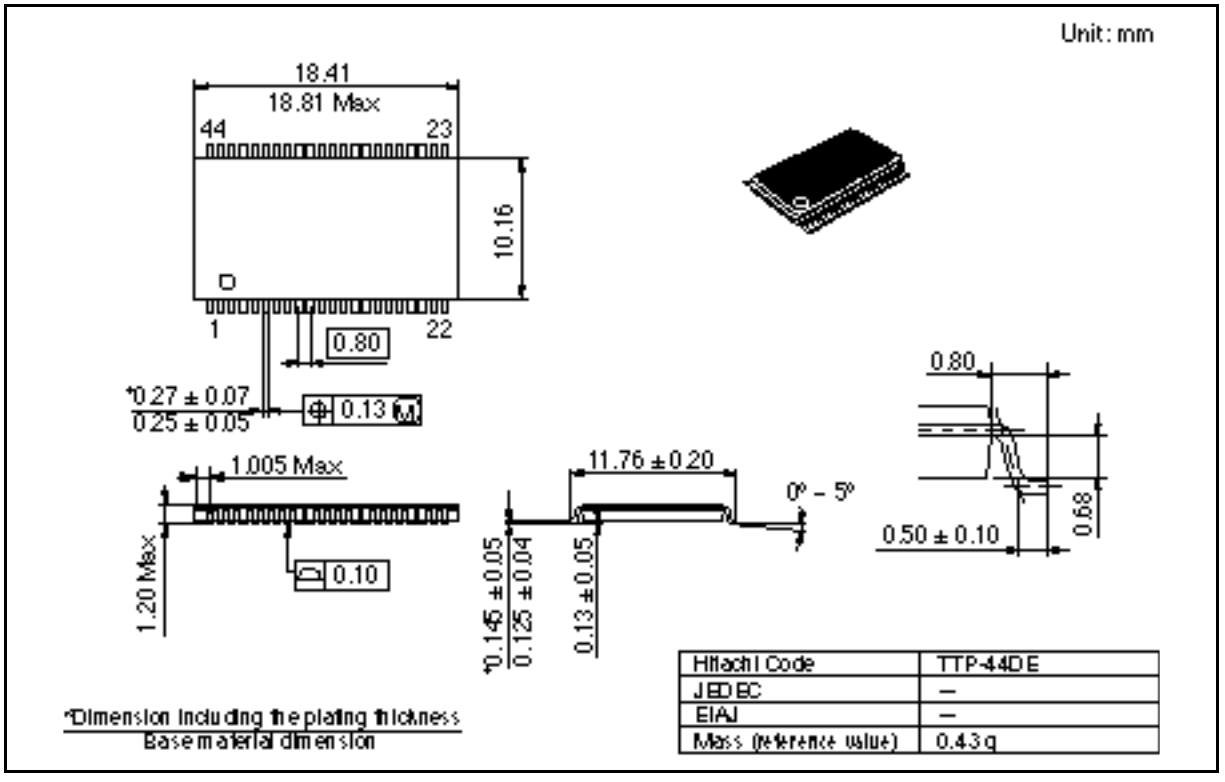
## Package Dimensions

**HM62W16255HCJPI Series** (CP-44D)




| | |
|---|---|
| Hitachi Code | CP-44D |
| JEDEC | Conforms |
| EIAJ | – |
| Mass (reference value) | 1.8 g |

**HM62W16255HCTTI Series** (TTP-44DE)



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